

<b>Notice of References Cited</b>	Application/Control No. 10/594,023		Applicant(s)/Patent Under Reexamination UENO ET AL.	
	Examiner Gene W. Lee		Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,320,562 B1	11-2001	Ueno et al.	345/87
*	B	US-2005/0275668 A1	12-2005	Feng, Xiao-fan	345/694
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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